

**Form PTO-1449 (modified)**

Statement of Patents and Publications for Applicant's
INFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)

Atty. Docket No.
METR:003

Serial No.
10/668,642

Applicant
Dale A. Harrison

Filing Date:
September 23, 2003

Group:
Unknown

U.S. Patent Documents
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Foreign Patent Documents
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U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
CH	A1	3,091,154	5/28/63	Hall			
CH	A2	4,899,055	2/6/90	Adams			
CH	A3	5,608,526	3/4/97	Piwonka-Corle et al.			
CH	A4	5,747,813	5/5/98	Norton et al.			
CH	A5	5,798,837	8/25/98	Aspnes et al.			
CH	A6	5,880,831	3/9/99	Buermann et al.			
CH	A7	5,900,939	5/4/99	Aspnes et al.			
CH	A8	5,991,022	4/27/99	Buermann et al.			
CH	A9	6,128,085	10/3/00	Buermann et al.			
CH	A10	6,181,427 B1	1/30/01	Yarussi, et al.			
CH	A11	6,278,519 B1	8/21/01	Rosencwaig et al.			
CH	A12	6,297,880 B1	10/2/01	Rosencwaig et al.			
CH	A13	6,304,326 B1	10/16/01	Aspnes et al.			
CH	A14	6,411,385 B2	6/25/02	Aspnes et al.			
CH	A15	6,414,302 B1	7/2/02	Freeouf			
CH	A16	6,417,921 B2	7/9/02	Rosencwaig et al.			
CH	A17	5,917,594	6/29/99	Norton			
CH	A18	Re. 34,783 E	11/8/94	Coates			
CH	A19	US2002/0149774	10/17/02	McAninch			
CH	A20	US2002/0154302	10/24/02	Rosencwaig et al.			
CH	A21	6,261,853 B1	7/17/01	Howell et al.			
CH	A22	5,182,618	1/26/93	Heinonen			
CH	A23	3,572,951	3/30/71	Rothwarf et al.			
CH	A24	US2003/0071996	4/17/03	Wang et al.			

Examiner: **CONSTANTINE HANNAHER** Date Considered: **SEP 9 2005**

EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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See Page 2-3**U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
	A25	Unknown		"Vacuum Ultraviolet Optical System for Operation in Ambient Atmosphere" Inventors: Michael J. Mandella & Dale A. Harrison Filed: 9/10/99 (Prior filed US Patent Application – current status unknown)			9/10/99

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C1	McPherson Product Brochure "Reflectometer for Sample Analysis," 3 pgs.
	C2	McPherson Product Brochure "VUVaS Spectrophotometers for 115 nm to >380 nm," 4 pgs.
	C3	McPherson Product Brochure "VUVaS Spectrophotometers, Made to Measure 115-380 nm," 8 pgs.
	C4	Acton Research Product Brochure "Acton Research Purged DAMS Optical Measurement System," 2 pgs.
	C5	"The Thin Film tool for next generation lithography at 157nm," Web page from http://www.sopra-sa.com , 1 pg.
	C6	"SE and GXR combined on the same instrument," Web page from http://www.sopra-sa.com , 1 pg.

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Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C7	"The ideal Thin Film characterization unit for Development and Pilot Line environment," Web page from http://www.sopra-sa.com , 1 pg.
	C8	"VUV-VASE™, The Award Winning VUV-VASE™ is the latest addition to our line of Spectroscopic Ellipsometers," Web pages from http://www.jawoolam.com , 2 pgs.
	C9	"Vacuum UV Spectroscopic Ellipsometers," Web pages from http://www.sentech.de , 3 pgs.

Examiner: CONSTANTINE HANNAHER | Date Considered: SEP 9 2005

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U.S. Patent Documents See Page 1	Foreign Patent Documents N/A	Other Art N/A	

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Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation

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Serial No.
10/668,642

Applicant
Dale A. Harrison

Filing Date:
September 23, 2003

Group:
2877

U.S. Patent Documents
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Foreign Patent Documents
N/A

Other Art
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U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
CH	A27	5,781,304	7/14/98	Kotidis et al.			2/14/97
CH	A28	2001/0055118A1	12/27/01	Nawracala			12/4/00
CH	A29	5,042,949	8/27/91	Greenberg et al.			3/17/89
CH	A30	3,825,347	7/23/74	Kaiser			8/9/71

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
CH	C10	Search Report;PCT/US04/30859; 13 pgs. not a publication

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